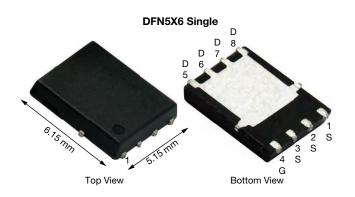


RoHS

COMPLIANT

119N03S-VB QFN8(5X6) Datasheet N-Channel 30-V (D-S) MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	R _{DS(on)} (Ω)	I _D (A) ^{a, e}	Q _g (Typ)		
30	0.007 at V _{GS} = 10 V	80	31 nC		
30	0.009 at V _{GS} = 4.5 V	60	31110		

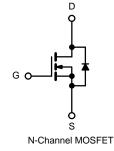


FEATURES

- Trench Power MOSFET ٠
- 100 % R_g and UIS Tested •
- Compliant to RoHS Directive 2011/65/EU •

APPLICATIONS

- OR-ing
- Server DC/DC



Parameter	Symbol	Lir	nit	Unit		
Drain-Source Voltage		V _{DS}	30		- V	
Gate-Source Voltage		V _{GS}	±			
	$T_{C} = 25 \text{ °C}$ $T_{C} = 70 \text{ °C}$		80			
Continuous Drain Current (T _J = 175 °C)			60		1	
$Continuous Drain Current (1_j = 175 C)$	T _A = 25 °C	Ι _D	50b, c		A	
	T _A = 70 °C		45 ^{b, c}			
Pulsed Drain Current		I _{DM}	210			
Avalanche Current Pulse	L = 0.1 mH	I _{AS}	60			
Single Pulse Avalanche Energy		E _{AS}	95	5	mJ	
Continuous Source-Drain Diode Current	T _C = 25 °C	L.	80 60		- A	
Continuous Source-Drain Diode Current	T _A = 25 °C	ا _S				
Maximum Power Dissipation	T _C = 25 °C	D	155		w	
	T _C = 70 °C	PD	105			
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to 175		°C	
THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Тур.	Max.	Unit	
Maximum Junction-to-Ambient ^{b, d}	$t \le 10 \text{ sec}$	R _{thJA}	32	40	°C/W	
Maximum Junction-to-Case	Steady State	R _{thJC}	0.5	0.6		

Notes:

a. Based on T_C = 25 °C. b. Surface mounted on 1" x 1" FR4 board.

c. t = 10 sec.

d. Maximum under steady state conditions is 90 °C/W.

e. Calculated based on maximum junction temperature. Package limitation current is 90 A.

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Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static						•
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 V, I_{D} = 250 \mu A$	30			V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I_{DS}/T_{J} $I_{D} = 250 \mu A$		35		m)//91
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	$I_D = 250 \mu A$		- 7.5		mV/°(
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_D = 250 \ \mu A$	0.5		2.0	V
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 V, V_{GS} = \pm 20 V$			± 100	nA
	1	$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}$			1	μA
Zero Gate Voltage Drain Current	IDSS	$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 55 \text{ °C}$			10	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, \text{ V}_{GS} = 10 \text{ V}$	90			Α
	D	V _{GS} = 10 V, I _D = 30.8 A		0.007		Ω
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = 4.5 \text{ V}, \text{ I}_{D} = 27 \text{ A}$		0.009		
Forward Transconductance ^a	9 _{fs}	V _{DS} = 15 V, I _D = 30.8 A		160		S
Dynamic ^b						•
Input Capacitance	C _{iss}				1180	pF
Output Capacitance	C _{oss}	V_{DS} = 15 V, V_{GS} = 0 V, f = 1 MHz			425	
Reverse Transfer Capacitance	C _{rss}				170	
Total Gate Charge	Qg	V_{DS} = 15 V, V_{GS} = 10 V, I_{D} = 30.8 A			61	nC
					31.5	
Gate-Source Charge	Q _{gs}	V_{DS} = 15 V, V_{GS} = 4.5 V, I_{D} = 27.8 A			10	
Gate-Drain Charge	Q _{gd}				6	
Gate Resistance	Rg	f = 1 MHz		1.4	2.1	Ω
Turn-On Delay Time	t _{d(on)}			18	27	- ns
Rise Time	t _r	V_{DD} = 15 V, R_L = 0.625 Ω		11	17	
Turn-Off Delay Time	t _{d(off)}	${\rm I_D}\cong$ 24 A, ${\rm V_{GEN}}$ = 10 V, ${\rm R_g}$ = 1 Ω		70	105	
Fall Time	t _f			10	15	
Turn-On Delay Time	t _{d(on)}			55	83	
Rise Time	t _r	V_{DD} = 15 V, R_L = 0.67 Ω		180	270	
Turn-Off Delay Time	t _{d(off)}	$\rm I_D \cong 22.5$ A, $\rm V_{GEN}$ = 4.5 V, $\rm R_g$ = 1 Ω		55	83	
Fall Time	t _f			12	18	
Drain-Source Body Diode Characteristic	cs					
Continuous Source-Drain Diode Current	۱ _S	T _C = 25 °C		60		A
Pulse Diode Forward Current ^a	I _{SM}			210		
Body Diode Voltage	V _{SD}	I _S = 22 A		0.8	1.2	V
Body Diode Reverse Recovery Time	t _{rr}			52	78	ns
Body Diode Reverse Recovery Charge	Q _{rr}	$\frac{Q_{rr}}{t_a}$ I _F = 20 A, di/dt = 100 A/µs, T _J = 25 °C		70.2	105	nC
Reverse Recovery Fall Time	t _a			27		
Reverse Recovery Rise Time	t _b			25		ns

Notes:

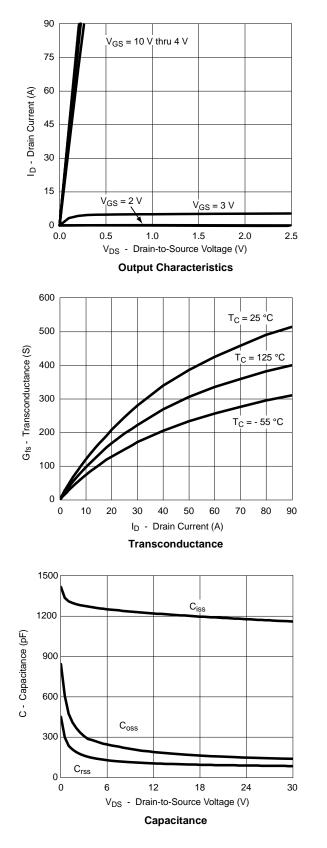
a. Pulse test; pulse width \leq 300 $\mu s,$ duty cycle \leq 2 %.

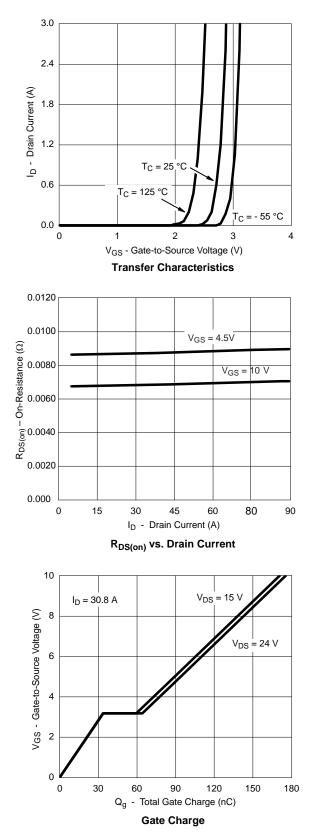
b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.



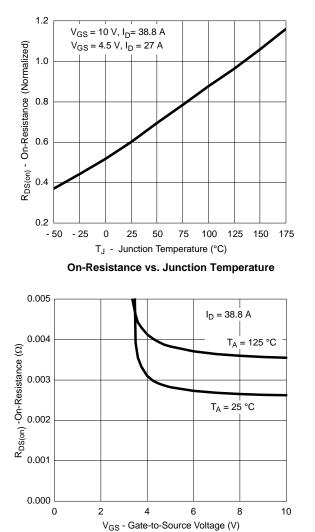
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



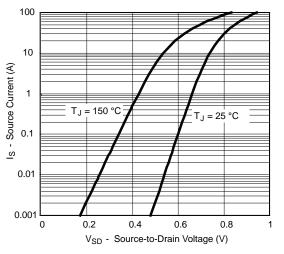




TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

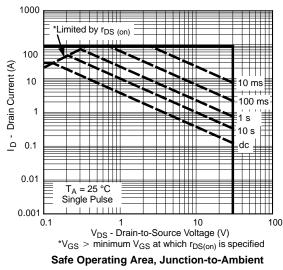


R_{DS(on)} vs. V_{GS} vs. Temperature

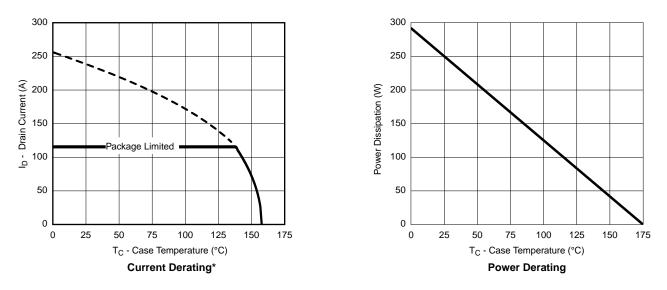


Forward Diode Voltage vs. Temperature



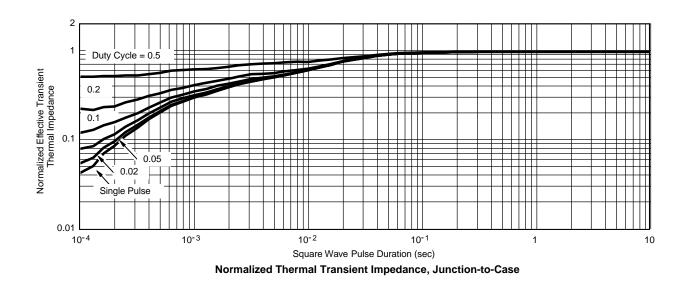






TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

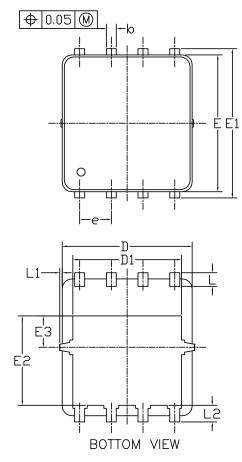
*The power dissipation P_D is based on $T_{J(max)} = 175$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

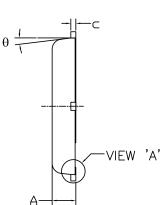


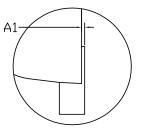
119N03S-VB QFN8(5X6)





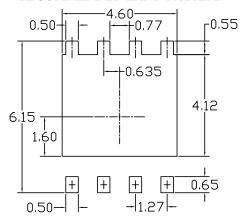






<u>VIEW 'A'</u> (SCALE 5:1)

RECOMMENDED LAND PATTERN



SYMBOLS	DIMENSIONS IN MILLIMETERS			DIMENSIONS IN INCHES		
SIMBOLS	MIN	NOM	MAX	MIN	NOM	MAX
А	0.85	0.95	1.00	0.033	0.037	0.039
A1	0.00		0.05	0.000		0.002
b	0.30	0.40	0.50	0.012	0.016	0.020
с	0.15	0.20	0.25	0.006	0.008	0.010
D	5.10	5.20	5.30	0.201	0.205	0.209
D1	4.25	4.35	4.45	0.167	0.171	0.175
E	5.45	5.55	5.65	0.215	0.219	0.222
E1	5.95	6.05	6.15	0.234	0.238	0.242
E2	3.525	3.625	3.725	0.139	0.143	0.147
E3	1.175	1.275	1.375	0.046	0.050	0.054
e	1.27 BSC			0.050 BSC		
L	0.45	0.55	0.65	0.018	0.022	0.026
L1	0		0.15	0		0.006
L2	0.68 REF			0.027 REF		
θ	0°		10°	0°		10°

NOTE

1. PACKAGE BODY SIZES EXCLUDE MOLD FLASH AND GATE BURRS.

MOLD FLASH AT THE NON-LEAD SIDES SHOULD BE LESS THAN 6 MILS EACH.

2. CONTROLLING DIMENSION IS MILLIMETER. CONVERTED INCH DIMENSIONS ARE NOT NECESSARILY EXACT.

UNIT: mm



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